

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Mikihiko ISHII et al. Group Art Unit: 2877

Application No.: 10/802,840 Examiner: M. LYONS

Filed: March 18, 2004 Docket No.: 119132

For: METHOD AND APPARATUS FOR POINT DIFFRACTION INTERFEROMETRY

<u>AMENDMENT</u>

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In reply to the February 9, 2005 Office Action, the shortened statutory period for reply being extended by the attached Petition for Extension of Time, please consider the following:

Amendments to the Specification;

Amendments to the Claims as reflected in the listing of claims;

Amendments to the Drawings include an attached replacement sheet; and

Remarks.